

Issue Classification

Application/Control No.

10789226

Applicant(s)/Patent Under Reexamination

OGAWA ET AL.

Examiner

Nguyen, Leon-Viet Q

Art Unit

2611

ORIGINAL

CLASS

SUBCLASS

375

148

INTERNATIONAL CLASSIFICATION

CLAIMED

NON-CLAIMED

H 0 4 B

1 / 00 (2006.01.01)

CROSS REFERENCE(S)

CLASS

SUBCLASS (ONE SUBCLASS PER BLOCK)

375

346

Nguyen, Leon-Viet Q

8/23/2007

(Assistant Examiner)

(Date)

(Legal Instruments Examiner)

9/12/07

(Date)

David Payne
DAVID C. PAYNE

SUPERVISORY PATENT EXAMINER

(Primary Examiner)

9/10/07

(Date)

Total Claims Allowed:

30

O.G. Print Claim(s)

1

O.G. Print Figure

2